

<b>Notice of References Cited</b>	Application/Control No. 10/618,468	Applicant(s)/Patent Under Reexamination TAN ET AL.	
	Examiner Gevell Selby	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0140837	10-2002	Miyake et al.	348/340
*	B	US-6,900,913	05-2005	Chen, Wen-Ching	348/243
*	C	US-2003/0016454	01-2003	Yamaguchi et al.	359/819
*	D	US-6,654,187	11-2003	Ning, Alex	359/819
*	E	US-2004/0113048	06-2004	Tu, Hsiu Wen	250/208.1
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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